

Publikationen

: Chapter 3: Fundamentals of CAFM Operation Modes. In: Conductive Atomic Force Microscopy: Applications in Nanomaterials, Weinheim.

: Academic domains as political battlegrounds. A global enquiry by 99 academics in the fields of education and technology. In: Information Development, vol. 33, no. 3, pp. 270-288. DOI: 10.1177/0266666916646415.

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